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## Neural Network Demodulation for an Optical Sensor

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(54) **NEURAL NETWORK DEMODULATION FOR AN OPTICAL SENSOR**

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**G02B 6/00** (2006.01)  
**G02B 6/26** (2006.01)  
**G02B 6/42** (2006.01)  
**G02B 6/34** (2006.01)

(52) **U.S. Cl.** ..... **385/12; 385/15; 385/31; 385/37**

(58) **Field of Classification Search** ..... None  
See application file for complete search history.

(56) **References Cited**

U.S. PATENT DOCUMENTS

5,180,911	A *	1/1993	Grossman et al. ....	250/227.21
5,564,832	A *	10/1996	Ball et al. ....	374/161
6,888,125	B2 *	5/2005	Ronnekleiv et al. ....	250/227.19
7,127,132	B1 *	10/2006	Moslehi et al. ....	385/12
2005/0046584	A1 *	3/2005	Breed .....	340/825.72

\* cited by examiner

*Primary Examiner*—Tina M Wong

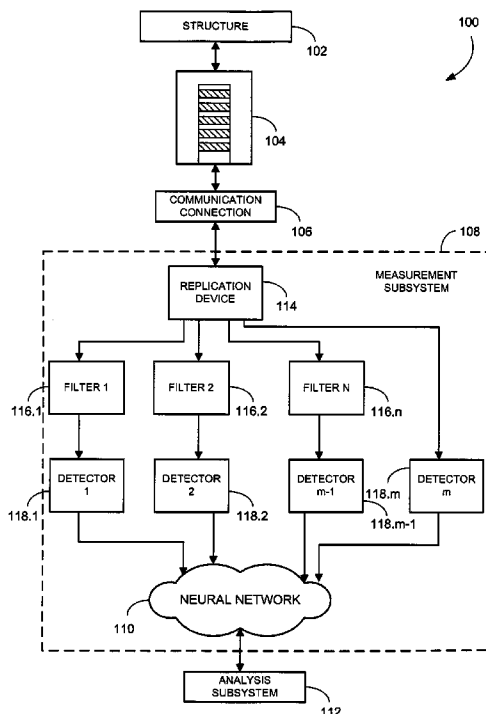
*Assistant Examiner*—Chris H Chu

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(57) **ABSTRACT**

Methods and systems of neural network demodulation for an optical sensor. An optical sensor may be coupled to a structure and be capable of reflecting a reflected optical signal. A wavelength of the reflected optical signal may be spread based on a strain being applied to the structure. A replication device may receive the reflected optical signal from the optical sensor and produce a plurality of optical signals. A filter may be coupled to the replication device to receive an optical signal from the plurality of optical signals and filter the received optical signal. A detector may receive the filtered optical signal and provide a voltage output proportional to an amount of the filtered optical signal received. A neural network may receive the voltage output and determine the strain on the structure.

**22 Claims, 8 Drawing Sheets**



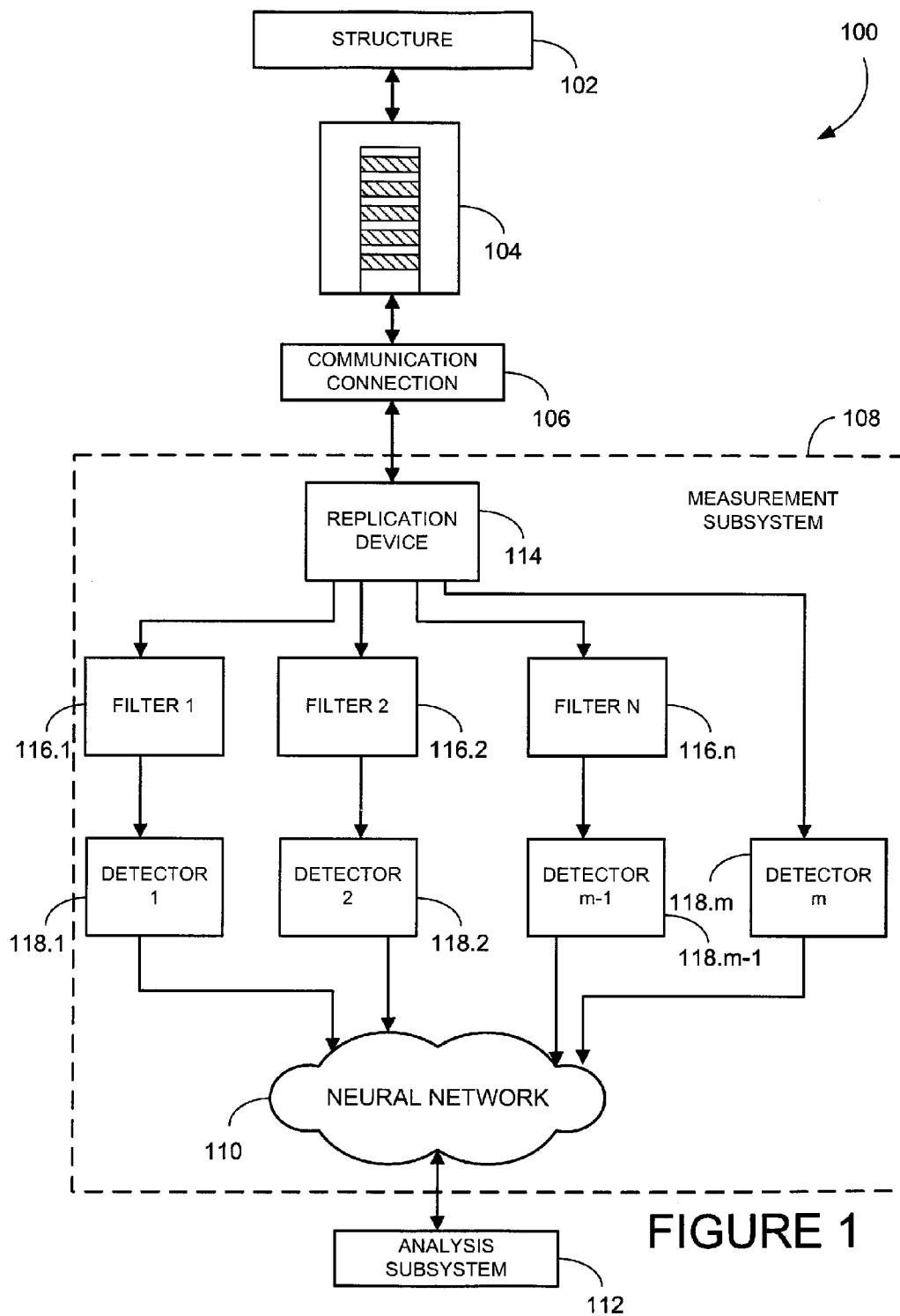


FIGURE 1

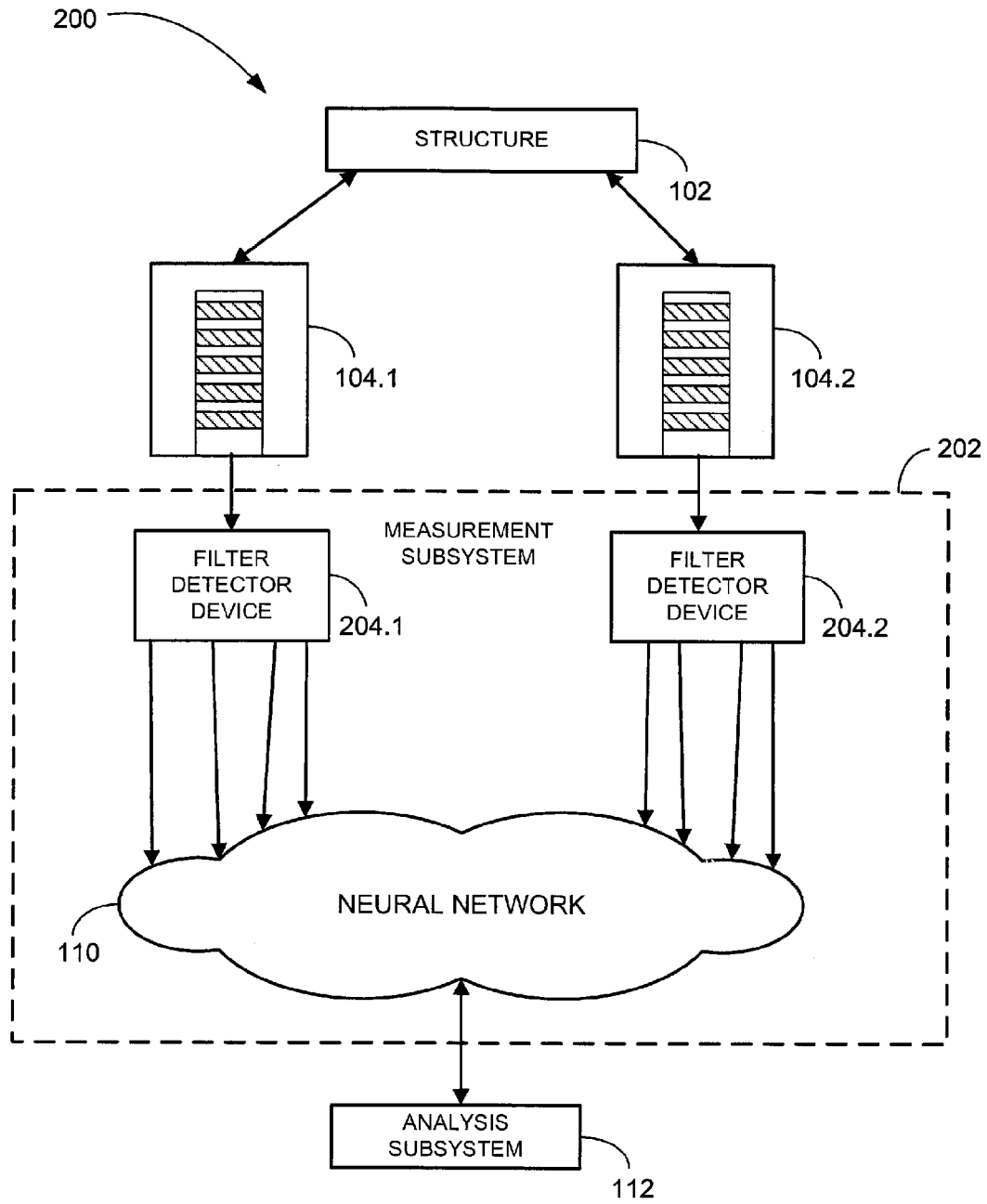


FIGURE 2

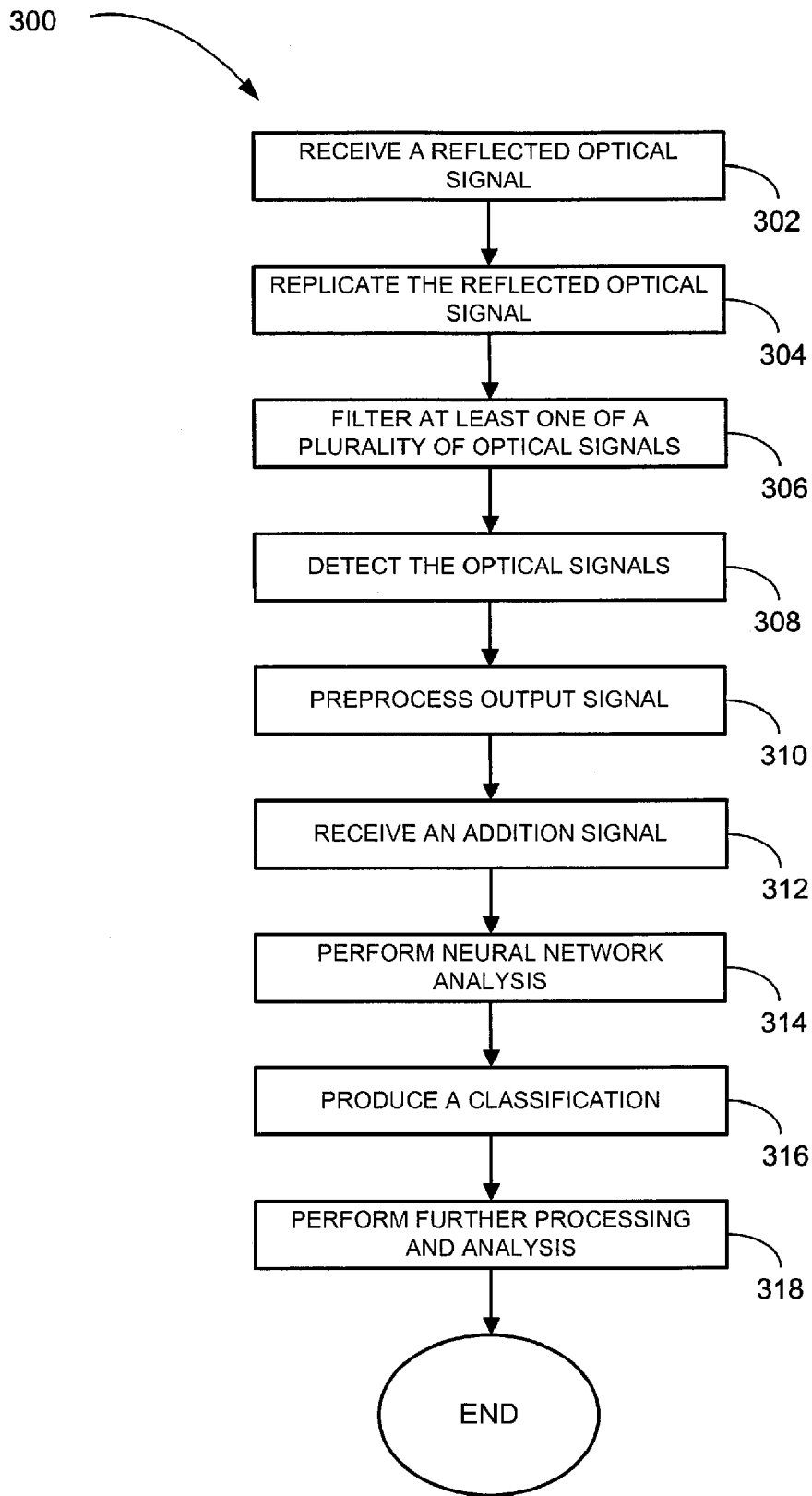


FIGURE 3

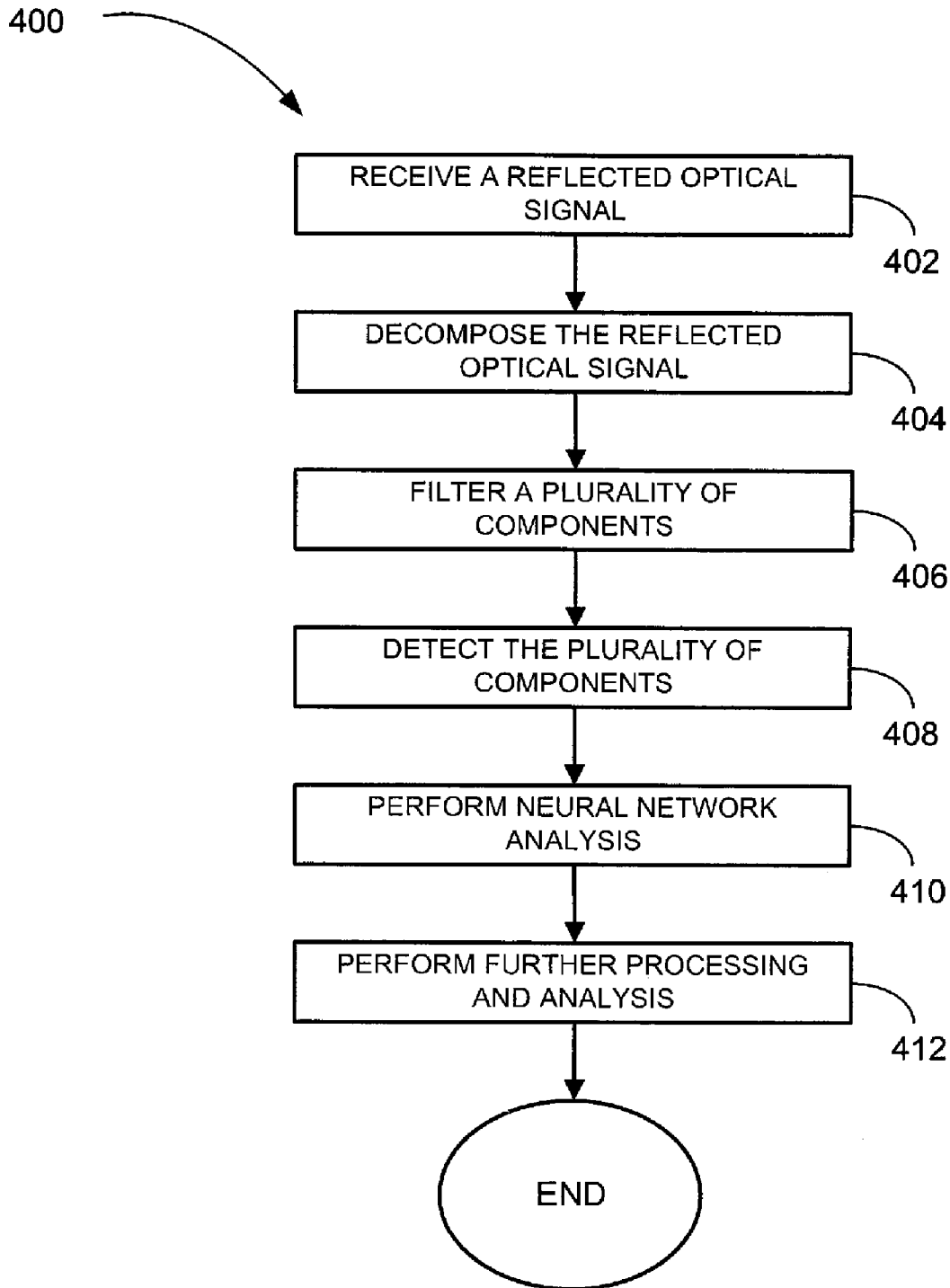


FIGURE 4

500

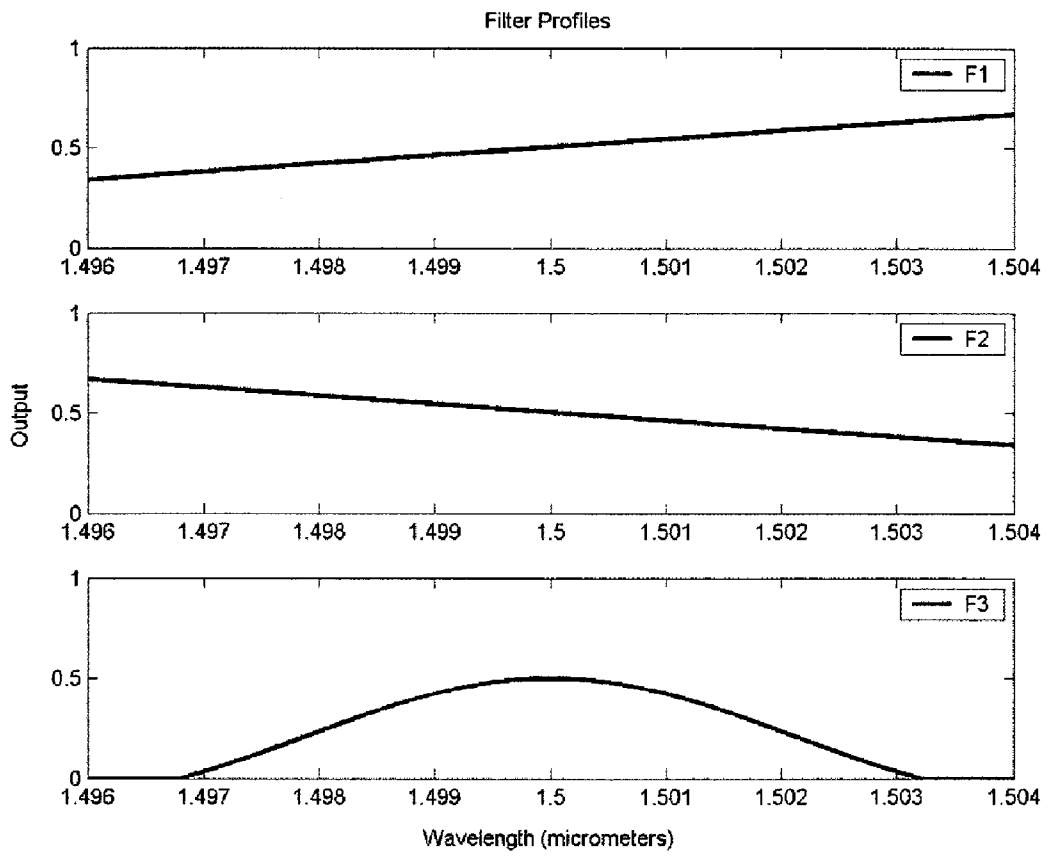


FIGURE 5

600

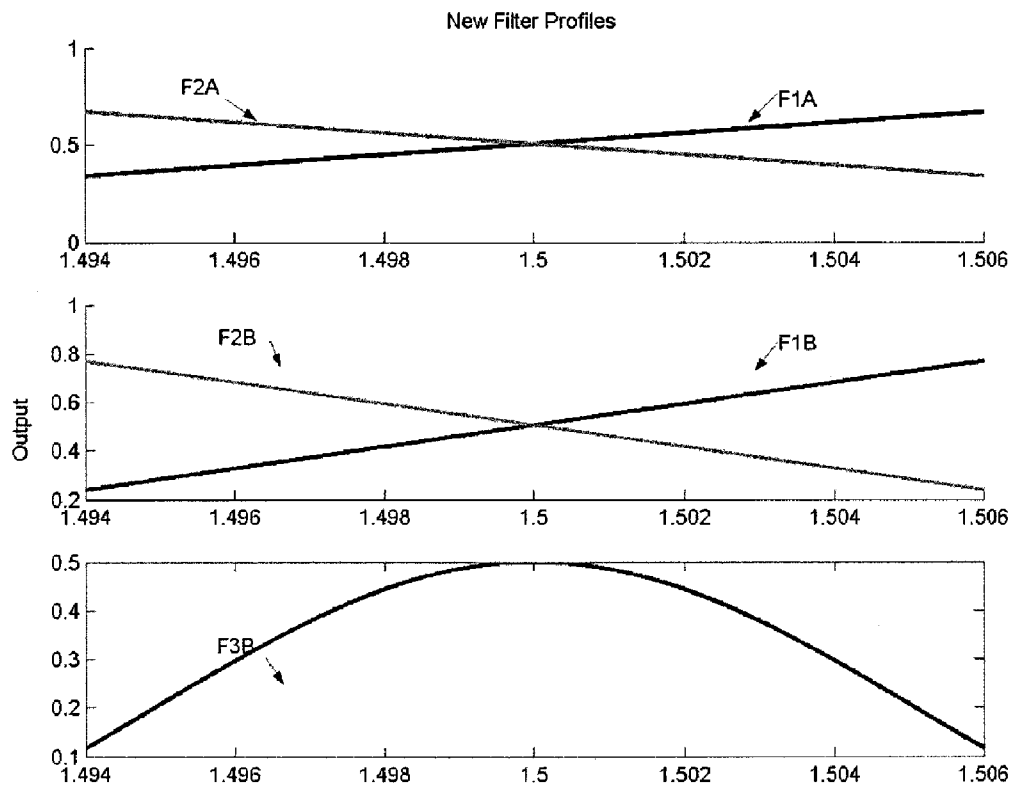


FIGURE 6



700

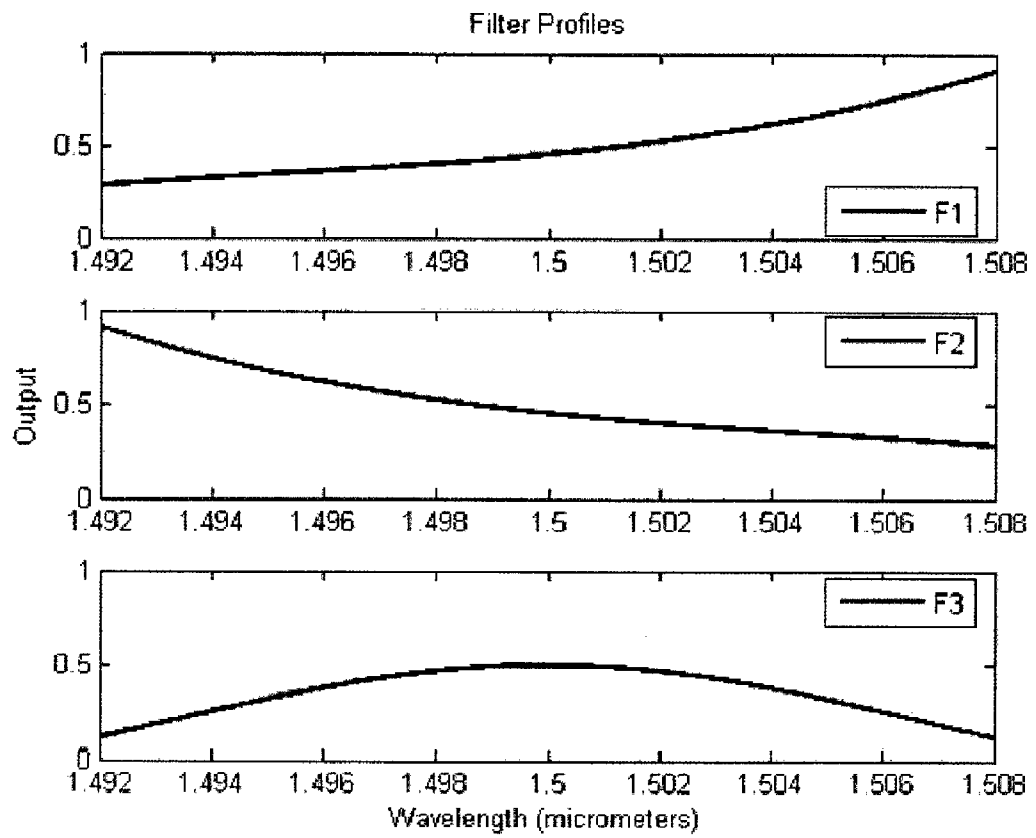


FIGURE 7

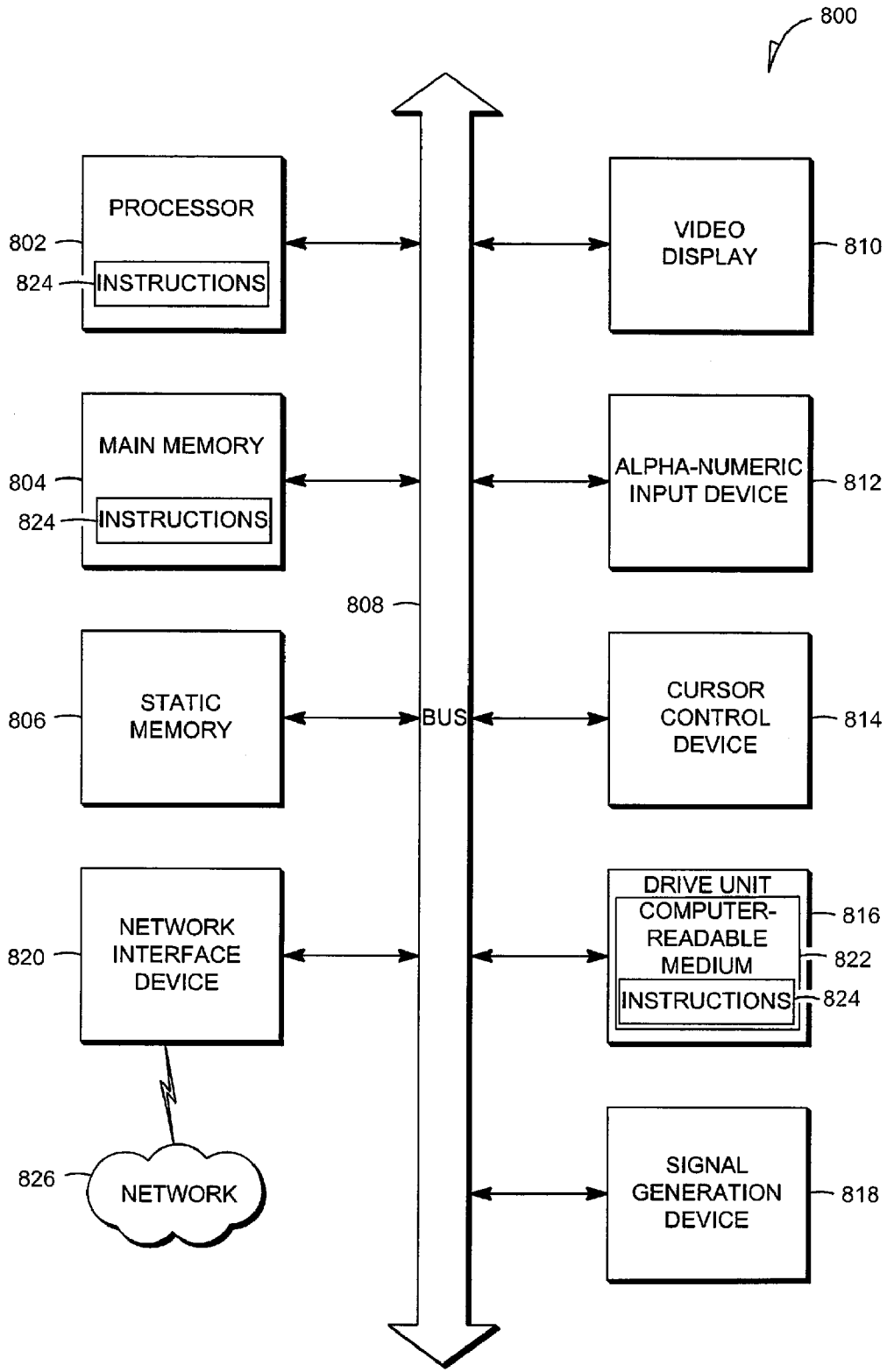


FIGURE 8

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## NEURAL NETWORK DEMODULATION FOR AN OPTICAL SENSOR

### CROSS-REFERENCE TO A RELATED APPLICATION

This application claims the benefit of U.S. Provisional Patent Application entitled "Neural Network Demodulator for Optical Sensor", Ser. No. 60/804,512, filed 12 Jun. 2006, the entire contents of which are herein incorporated by reference.

### TECHNICAL FIELD

The present application relates generally to the field of signal processing and, in one specific example, to a method and system for demodulating an optical signal using a neural network.

### BACKGROUND

Strain sensing is used in a Health Monitoring System (HMS) for civilian, mechanical, and aerospace applications. The choice of sensor types for a given sensing application may depend upon a parameter being measured and the physical properties of the sensor. The parameter being measured can be strain, temperature, pressure, or force on a structure.

Common fiber optic sensors may be based on interferometric, attenuation, and spectral effects. Two major categories of fiber optic strain sensors are the Fabry-Perot interferometric and Bragg grating sensors. The irradiance output changes with strain for Fabry-Perot sensors and the wavelength output changes with strain for Bragg grating sensors. The relationship between the irradiance output and applied strain may be highly non-linear for Fabry-Perot sensors, where as the spectral shift may be linear for Bragg grating sensors. This linear property may make Bragg gratings desired sensors in strain sensing applications.

### BRIEF DESCRIPTION OF THE DRAWINGS

Some embodiments are illustrated by way of example and not limitation in the figures of the accompanying drawings in which:

FIGS. 1-2 are block diagrams of a measurement system for a structure according to an example embodiment;

FIGS. 3-4 illustrate a method for optical detection analysis according to an example embodiment;

FIGS. 5-7 illustrate a chart of filter profiles according to an example embodiment; and

FIG. 8 shows a diagrammatic representation of machine in the example form of a computer system within which a set of instructions for causing the machine to perform any one or more of the methodologies discussed herein may be executed.

### DETAILED DESCRIPTION

Example methods and systems for neural network demodulation for an optical sensor are described. In the following description, for purposes of explanation, numerous specific details are set forth in order to provide a thorough understanding of example embodiments. It will be evident, however, to one skilled in the art that the present invention may be practiced without these specific details.

In an example embodiment, an optical sensor may be coupled to a structure. The optical sensor may receive a source optical signal and reflect a reflected optical signal. At least one wavelength of the reflected optical signal may be spread based on a strain being applied to the structure. A

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replication device may be coupled to the optical sensor. The replication device may receive the reflected optical signal from the optical sensor and produce a plurality of optical signals. At least one filter may be coupled to the replication device to receive an optical signal from the plurality of optical signals and filter the received optical signal. At least one detector may be coupled to the at least one filter to receive the filtered optical signal and provide an output signal representing an amount of the filtered optical signal received. A neural network may be coupled to the at least one detector. The neural network may receive the output signal from the at least one detector and determine the strain on the structure.

In an example embodiment, a reflected optical signal may be received from an optical sensor. The optical sensor may be coupled to a structure. At least one wavelength of the reflected optical signal may be spread based on a strain being applied to the structure. The reflected optical signal may be replicated to produce a plurality of optical signals. At least one of the plurality of optical signals may be filtered to produce at least one filtered optical signal. The at least one filtered optical signal may be detected to determine an output signal representing an amount of the at least one filtered optical signal. A neural network analysis may be performed on the output signal to determine an amount of strain applied to the structure.

In an example embodiment, a reflected optical signal may be received from an optical sensor. The optical sensor may be coupled to a structure. At least one wavelength of the reflected optical signal may be spread based on a strain being applied to the structure. The reflected optical signal may be decomposed to produce a plurality of different components of the reflected optical signal. The plurality of different components may be filtered to produce a plurality of filtered components. The plurality of filtered components may be detected to determine an output signal representing an amount of the at least one filtered optical signal. A neural network analysis may be performed on the signal output to determine an amount of strain applied to the structure.

FIG. 1 illustrates an analysis system 100 according to an example embodiment. The analysis system 100 includes an optical sensor 104 coupled to a structure 102. The optical sensor 104 receives a source optical signal and reflects a reflected optical signal with at least one wavelength of the reflected optical signal being spread based on a strain being applied to the structure 102. The optical sensor 104 may be a fiber optical sensor (e.g., a Bragg optical grating sensor), however other types of sensors may also be used.

The structure 102 may be, for example, an automotive structure, an aircraft structure, or a civil engineering structure. For example, if the analysis system 100 is deployed in a civil application, the optical sensor 104 may be attached underneath a bridge or to a beam in a building. The analysis system 100 may be used to monitor health of the structure 102 to determine whether, for example, the structure is in danger of buckling or collapsing. The analysis system 100 may be used to monitor strain, movement, integrity, and the like.

The analysis system 100 may further include a measurement subsystem 108 coupled to the optical sensor 104 through a communication connection 106. The measurement subsystem 108 may be used for sensing that may lead to a shift in wavelength. For example, the measurement subsystem 108 may be used for one or more parameters that may be associated with the shift such as strain sensing, temperature sensing, pressure sensing, force on the structure 102 and the like.

The communication connection 106 may be fiber, a cable, a wire, an optical transmission medium, or the like through which wavelengths of light or their equivalents may travel from the optical sensors 104 to a measurement subsystem 108.

By way of an example, when wavelengths of an optical signal are sent through the communication connection 106, the optical sensor 104 may reflect a narrow band of the wavelengths of the optical signal to the measurement subsystem 108. If the structure 102 is under a strain, the optical sensor 104 may be stretched. The stretching of the optical sensor 104 may cause a reflection from a mechanism within the optical sensor 104 to shift a spread of the wavelengths of light that returns to the measurement subsystem 108. By determining the shift of the spread of the wavelengths of the optical signal, the stretch on the structure 102 may also be determined.

The measurement subsystem 108 may include a replication device 114, one or more filters 116.1-116.n, and/or one or more detectors 118.1-118.m. The replication device 114 may be coupled to the optical sensor 104 through the communication connection 106. The replication device 114 receives the reflected optical signal from the optical sensor 104 and produces a plurality of optical signals. For example, the replication device 114 may be a splitter, an expander, or the like. The replication device 114 may include a lens or a Tensing system (e.g., a circularizing lens) and/or an optical grating. For example, the replication device 114 may include a lens that may spread out the reflected optical signal and provide the plurality of optical signals to the one or more filters 116.1-116.n.

The measurement subsystem 108 may demodulate a spectral shift in the reflected optical signal for purposes of measurement (e.g., strain measurement) by using, for example, multiple channels for processing a reflected optical signal to overcome limitations (e.g., noise) within the analysis system 100.

The one or more filters 116.1-116.n are coupled to the replication device 114 to receive an optical signal from the plurality of optical signals and filter the received optical signal. The spectral characteristics of the filters 116.1-116.n may be known to the measurement subsystem 108.

The filters 116.1-116.n may include a filter that changes output upon receiving a change in wavelength or spectrum from the optical sensor 104. For example, a filter profile of the filters 116.1-116.n may include a first filter profile that is monotonically increasing with wavelength, a second filter profile that is monotonically decreasing with wavelength, and a third filter profile that is roughly centered with a zero strain point of the optical sensor 104.

The one or more filters 116.1-116.n may include one or more interferometric filters and/or one or more absorption filters. Other types of filters may also be used.

The one or more filters 116.1-116.n may include at least one filter having a linear or close-to-linear characteristic and/or a nonlinear characteristic. A type of the filters 116.1-116.n selected for use within the measurement subsystem 108 may include a filter section that provides a positive slope and a negative slope in response to strain in the structure 102. For example, the positive slope and the negative slope may be linear or near linear over a string range.

The one or more filters 116.1-116.n may include a low profile filter, a high profile filter and a band pass profile filter. For example, the low profile filter and the high profile filter may provide a nearly linear change in the filtered optical signals provided to the one or more detectors 118.1-118.m. All of the one or more filters 116.1-116.n need not extract strain information, but may extract additional information.

In an example embodiment, an optical to digital conversion or an optical to analog conversion may occur prior to the receipt of the plurality of optical signals by the one or more filters 116.1-116.n. A spectrum analyzer may be used for analyzing the optical signal.

The one or more detectors 118.1-118.m may receive the filtered optical signal and provide an output signal representing an amount of the filtered optical signal received. For

example, the output signal may be a voltage output that is proportional to an amount of the filtered optical signal received. The one or more detectors 118.1-118.m may each be coupled to either one or more filters 116.1-116.n or directly to the replication device 114. The optional unfiltered reflected optical signal received from the replication device 114 may act as a normalizing factor. An output from the detectors 118.1-118.m may be scaled from -1 to 1.

The one or more detectors 118.1-118.m may collectively include one or more photodetectors. For example, the one or more detectors 118.1-118.m may collectively be a single photodetector (e.g., a quad photodetector).

A number of the filters 116.1-116.n may be equal to a number of the detectors 118.1-118.m or less than a number of the detectors 118.1-118.m.

A neural network 110 (e.g., an artificial neural network) is coupled to the one or more detectors 118.1-118.m. The neural network 110 may be capable of receiving the output signal from the one or more detectors 118.1-118.m and determining the measurement data (e.g., strain) on the structure 102. The neural network 110 may be pretrained on, have solved for from mathematical or other models, adapt in real-time, or otherwise have access to the characteristics of the filters 116.1-116.n and use the characteristics when determining the strain on the structure 102.

The neural network 110 may be a type of neural network that is capable of performing regression or function approximation. For example, the neural network 110 may be a simple neural network or a complex neural network. The neural network 110 may include an interconnected assembly of simple processing elements and/or a multi-layered feedforward neural network.

The neural network 110 may include a two layer network with a hidden layer and an output layer. A number of neurons in the hidden layer may differ based on application of the measurement subsystem 108. Transfer functions for neurons in the hidden and the output layer of the neural network 110 may be hyperbolic tangent and linear, respectively. Other types of networks and/or transfer functions may also be used.

A processing ability of the neural network 110 may be stored in the interunit connection strengths obtained by a process of adaptation to, or learning from, a set of training patterns. In an example embodiment, the training and testing of the neural network 110 may be performed using MATLAB 'Neural Network Toolbox'. The neural network 110 may be implemented with or without special software tools for development of the neural network 110.

The neural network 110 may be trained using a Levenberg-Marquardt training algorithm, backpropagation training algorithm (BPNN), Adaptive Resonance Theory, Probabilistic Neural Networks, Support Vector Machines, Extended Kalman Filter, Particle Swarm Optimization, and/or Genetic Algorithms. However, other training algorithms may also be used.

Statistical learning techniques may be used to train the neural network 110. The neural network 110 may be a training system with applied statistical learning techniques that convert the training system into a set of rules.

The neural network 110 may receive an additional signal such as a signal from an additional temperature sensor. For example, the additional sensor may include a temperature sensor so that the neural network 110 may provide adequate temperature compensation (e.g., for ambient temperature). The additional sensor may include a sensor capable of receiving a time and date signal, humidity, wind speed and tides and other environmental factors, and the like.

A complexity of the neural network 110 may be based on a precision of measurement desired. For example, if a user wants to detect a strain using the analysis system 100 with a

resolution of five micro strain, a simpler neural network system **110** as compared to if the user wants the resolution to be one micro strain.

The complexity of the neural network **110** may be based on noise in the analysis system **100**, attenuation in the analysis system **100**, problems encountered in making a reading using the measurement subsystem **108** and the like. For example, a first neural network **110** may use twenty to thirty neurons, a second neural network **110** that is reading a temperature composition may use fifty to sixty neurons, and a third neural network **110** with noise and attenuation problems may use up to one hundred neurons.

The detectors **118.1-118.m** may provide parallel inputs to the neural network **110** to enable an absolute strain or shift in the optical signal to be detected.

A further signal provided from the neural network **110** to an analysis subsystem **112** may indicate a measured amount of strain. The analysis subsystem **112** may optically be coupled to the neural network **110** to receive the further signal for further processing and analysis.

The measurement subsystem **108** and the analysis subsystem **112** may be combined into a combination device or individually implemented on one or more devices. The devices may include a single processor or multiple processors for purposes including speed and parallel processing.

FIG. 2 illustrates an analysis system **200** according to an example embodiment. Multiple optical sensors **104.1, 104.2** may be coupled to the structure **102** to measure more than one parameter of the structure. The optical sensors **104.1, 104.2** may respectively be coupled to multiple filter detector devices **204.1, 204.2** that include the replication device **114**, the one or more filters **116.1-116.n** and the one or more detectors **118.1** (see FIG. 1). For example, the multiple filters **116.1-116.n** may each be in front of a plurality of components of a quad photodetector.

The filter detector devices **204.1, 204.2** may provide an output to the neural network **110**, which may then provide a further output to the analysis subsystem **112**.

The measurement subsystem **202** may be used with the optical sensor **104.1** as a dummy sensor to enable, by way of example, an additional environmental factor such as humidity, wind speed and tides to be considered.

FIG. 3 illustrates a method **300** for optical detection analysis according to an example embodiment. The method **300** may be performed by the measurement subsystem **108**, the measurement subsystem **202**, or another device according to an example embodiment.

A reflected optical signal is received from the optical sensor **104** coupled to the structure **102** at block **302**. The reflected optical signal may be received in response to an original optical signal sent to the optical sensor and at least one wavelength of the reflected optical signal may be spread relative to the original optical signal based on a strain being applied to the structure **102**. The at least one wavelength of the reflected optical signal may be a center wavelength (e.g., with a linear shift) or another wavelength.

A change in an output of the optical sensor **104** for an applied strain to the structure **102** may be characterized by a linear shift in a center wavelength. A center wavelength for the optical sensor **104** may be  $1.5\ \mu\text{m}$ , while a working range of the wavelengths may be  $1.496\ \mu\text{m}$  to  $1.504\ \mu\text{m}$ . For example, when three strain values  $-3000\ \mu\epsilon$ ,  $0\ \mu\epsilon$  and  $+3000\ \mu\epsilon$  are used, a linear shift centered near  $1.496\ \mu\text{m}$  may be observed for  $-3000\ \mu\epsilon$ , no shift may be observed for  $0\ \mu\epsilon$ , and a linear shift centered near  $1.504\ \mu\text{m}$  may be observed for  $+3000\ \mu\epsilon$ . Other center wavelengths and working ranges may be used.

The shift in the center wavelength may be approximately linear with respect to applied strain and temperature. The

spectrum of the reflected optical signal may only be shifted and a distribution around a center wavelength may not change.

The reflected optical signal is replicated to produce a plurality of optical signals at block **304**. For example, each of the plurality of optical signals may have same characteristics as the reflected optical signal. At least one of the plurality of optical signals is filtered to produce at least one filtered optical signal at block **306**.

At block **308**, the filtered optical signal is detected to determine an output signal representing an amount of the filtered optical signal. An unfiltered optical signal may optically be detected at block **308** from the plurality of optical signals to determine the output signal representing an amount of the unfiltered optical signal.

The output signal may be preprocessed at block **310**. For example, preprocessing the voltage output may include scaling the output signal or normalizing the output signal. Other types of preprocessing may also be performed. Preprocessing may be used with training the neural network **110**.

An additional signal may be received from an additional sensor at block **312**. The sensor additional may be a temperature sensor, a time and date sensor, or an environmental factor sensor.

The neural network analysis is performed at block **314** to determine the amount of strain applied to the structure **102**. The neural network **110** may process the information received and, based on training, provide a strain analysis while taking into consideration noise. The neural network analysis may be performed on the output signal, the preprocessed output, or on the output signal using the additional signal.

In an example embodiment, the neural network **110** may be trained prior to performing the operations at block **314** to account for variations in the analysis system **100**. For example, the neural network **110** may be trained to account for variations in a source optical signal sent from a light source, signal loss in the communication connection **106**, variations in the one or more filters **116.1-116.n** and the like.

The neural network **110** may be developed for changing field parameters such as noise, filter non-linearity and amplitude variation and to account for practical issues regarding source, filters, and multiplexing. The neural network **110** may be trained to handle a profile of the one or more filters **116.1-116.n**.

A classification may be produced on the strain at block **316**. The classification may include a user-defined category (e.g., severe, moderate, or mild), classification of the damage that may have resulted from the strain, or the like. The classification may be refined before or after it is provided to a user by observation of the strain and/or damage by use of other techniques and/or training of the neural network **110**.

At block **318**, further processing and analysis may optionally be performed on the amount of strain applied to the structure **102**.

FIG. 4 illustrates a method **400** for optical detection analysis according to an example embodiment. The method **400** may be performed by measurement subsystem **108**, the measurement subsystem **202**, or another device according to an example embodiment.

A reflected optical signal is received from the optical sensor **104** coupled to the structure **102** at block **402**.

At block **404**, the reflected optical signal is decomposed to produce a plurality of different components of the reflected optical signal. Decomposing information from the reflected optical signal may be providing different components of the reflected optical signal to the one or more filters **116.1-116.n**.

The plurality of different components is filtered to produce a plurality of filtered components at block **406**.

The plurality of filtered components is detected at block **408** to determine an output signal representing an amount of the at least one filtered optical signal.

A neural network analysis is performed at block **410** on the output signal to determine an amount of strain applied to the structure **102**.

At block **412**, further processing and analysis may be performed on the amount of strain applied to the structure **102**.

FIG. **5** illustrates a chart **500** including three filter profiles **F1**, **F2** and **F3**. The three filter profiles **F1**, **F2** and **F3** may each be a subsection of filter profiles of the one or more filters **116.1-116.n**. The three filter profiles **F1**, **F2** and **F3** may each provide a signal with a shift in wavelength resulting from an application of a strain.

The detected signals from the one or more detectors **118.1-118.m** may be proportional to integration of a spectrum of the reflected optical signal multiplied by a respective filter. One or more detectors **118.1-118.m** may calculate an unfiltered signal that may act as a normalizing factor.

FIG. **6** illustrates a chart **600** including five filter profiles **F1A**, **F2A**, **F1B**, **F2B** and **F3B**. The filter profiles **F1A** and **F2A** may have a same intercept as filter profiles **F1** and **F2** (see FIG. **5**) with a wavelength range that has been increased to 1.494  $\mu\text{m}$  to 1.506  $\mu\text{m}$ . The filter profiles **F2B** and **F1B** may have a slightly higher intercept, while the filter profile **F3B** may be broader than the filter profile **F3** (see FIG. **5**).

FIG. **7** illustrates a chart **700** including three filter profiles **F1**, **F2**, **F3**. The three filter profiles **F1**, **F2**, **F3** may each be the filter profiles of FIG. **1** over an extended wavelength.

FIG. **8** shows a diagrammatic representation of machine in the example form of a computer system **800** within which a set of instructions, for causing the machine to perform any one or more of the methodologies discussed herein, may be executed. In alternative embodiments, the machine operates as a standalone device or may be connected (e.g., networked) to other machines. In a networked deployment, the machine may operate in the capacity of a server or a client machine in server-client network environment, or as a peer machine in a peer-to-peer (or distributed) network environment. The machine may be a personal computer (PC), a tablet PC, a set-top box (STB), a television, a Personal Digital Assistant (PDA), a cellular telephone, a portable music player (e.g., a portable hard drive audio device such as an MP3 player), a car audio device, a web appliance, a network router, switch or bridge, an encoder, a detector, or any machine capable of executing a set of instructions (sequential or otherwise) that specify actions to be taken by that machine. Further, while only a single machine is illustrated, the term "machine" shall also be taken to include any collection of machines that individually or jointly execute a set (or multiple sets) of instructions to perform any one or more of the methodologies discussed herein.

The example computer system **800** includes a processor **802** (e.g., a central processing unit (CPU) a graphics processing unit (GPU) or both), a main memory **804** and a static memory **806**, which communicate with each other via a bus **808**. The processor **802** may represent a central processing unit of any type of architecture, such as a CISC (Complex Instruction Set Computing), RISC (Reduced Instruction Set Computing), VLIW (Very Long Instruction Word), or a hybrid architecture, although any appropriate processor may be used. The processor **802** may execute instructions and includes that portion of the computer system **800** that controls the operation of the entire computer system **800**.

The computer system **800** may further include a video display unit **810** (e.g., a liquid crystal display (LCD) or a cathode ray tube (CRT)). The computer system **800** also includes an alphanumeric input device **812** (e.g., a keyboard),

a cursor control device **814** (e.g., a mouse), a disk drive unit **816**, a signal generation device **818** (e.g., a speaker) and a network interface device **820**.

The cursor control device **814** may be a keyboard, mouse or other pointing device, trackball, touchpad, touch screen, keypad, microphone, voice recognition device, or any other appropriate mechanism for the user to input data to the computer **800** and manipulate the user interface previously discussed. Although only one input device **814** is shown, in another embodiment any number and type of input devices may be present.

The disk drive unit **816** includes a machine-readable medium **822** on which is stored one or more sets of instructions (e.g., software **824**) embodying any one or more of the methodologies or functions described herein. The software **824** may also reside, completely or at least partially, within the main memory **804** and/or within the processor **802** during execution thereof by the computer system **800**, the main memory **804** and the processor **802** also constituting machine-readable media.

The software **824** may further be transmitted or received over a network **826** via network interface device **820**. The network **826** may be any suitable network and may support any appropriate protocol suitable for communication to the computer system **800**. In an embodiment, the network **826** may support wireless communications. In another embodiment, the network **826** may support hard-wired communications, such as a telephone line or cable. In another embodiment, the network **826** may support the Ethernet IEEE (Institute of Electrical and Electronics Engineers) 802.3x specification. In another embodiment, the network **826** may be the Internet and may support IP (Internet Protocol). In another embodiment, the network **826** may be a local area network (LAN) or a wide area network (WAN). In another embodiment, the network **826** may be a hotspot service provider network. In another embodiment, the network **826** may be an intranet. In another embodiment, the network **826** may be a GPRS (General Packet Radio Service) network. In another embodiment, the network **826** may be any appropriate cellular data network or cell-based radio network technology. In another embodiment, the network **826** may be an IEEE 802.12 wireless network. In still another embodiment, the network **826** may be any suitable network or combination of networks. Although one network **826** is shown, in other embodiments any number of networks (of the same or different types) may be present.

While the machine-readable medium **822** is shown in an example embodiment to be a single medium, the term "machine-readable medium" should be taken to include a single medium or multiple media (e.g., a centralized or distributed database, and/or associated caches and servers) that store the one or more sets of instructions. The term "machine-readable medium" shall also be taken to include any medium that is capable of storing, encoding or carrying a set of instructions for execution by the machine and that cause the machine to perform any one or more of the methodologies of the present invention. The term "machine-readable medium" shall accordingly be taken to include, but not be limited to, solid-state memories, optical and magnetic media, and carrier wave signals.

The computer system **800** may be implemented using any suitable hardware and/or software, such as a personal computer or other electronic computing device. Encoders, detectors, portable computers, laptop or notebook computers, PDAs (Personal Digital Assistants), pocket computers, appliances, telephones, and mainframe computers are examples of other possible configurations of the computer system **800**. For

example, other peripheral devices such as audio adapters or chip programming devices, such as EPROM (Erasable Programmable Read-Only Memory) programming devices may be used in addition to, or in place of, the hardware already depicted.

Although the present invention has been described with reference to specific example embodiments, it will be evident that various modifications and changes may be made to these embodiments without departing from the broader spirit and scope of the invention. Accordingly, the specification and drawings are to be regarded in an illustrative rather than a restrictive sense.

Certain systems, apparatus, applications or processes are described herein as including a number of modules or mechanisms. A module or a mechanism may be a unit of distinct functionality that can provide information to, and receive information from, other modules. Accordingly, the described modules may be regarded as being communicatively coupled. Modules may also initiate communication with input or output devices, and can operate on a resource (e.g., a collection of information). The modules be implemented as hardware circuitry, optical components, single or multi-processor circuits, memory circuits, software program modules and objects, firmware, and combinations thereof, as appropriate for particular implementations of various embodiments.

The Abstract of the Disclosure is provided to comply with 37 C.F.R. §1.72(b), requiring an abstract that will allow the reader to quickly ascertain the nature of the technical disclosure. It is submitted with the understanding that it will not be used to interpret or limit the scope or meaning of the claims. In addition, in the foregoing Detailed Description, it can be seen that various features are grouped together in a single embodiment for the purpose of streamlining the disclosure. This method of disclosure is not to be interpreted as reflecting an intention that the claimed embodiments require more features than are expressly recited in each claim. Rather, as the following claims reflect, inventive subject matter lies in less than all features of a single disclosed embodiment. Thus the following claims are hereby incorporated into the Detailed Description, with each claim standing on its own as a separate embodiment.

What is claimed is:

**1.** A system comprising:

an optical sensor coupled to a structure, the optical sensor to receive a source optical signal and reflect a reflected optical signal, at least one wavelength of the reflected optical signal being spread based on a strain being applied to the structure;

a replication device coupled to the optical sensor, the replication device to receive the reflected optical signal from the optical sensor and produce a plurality of optical signals;

at least one filter coupled to the replication device to receive an optical signal from the plurality of optical signals and filter the received optical signal;

at least one detector, coupled to the at least one filter, to receive the filtered optical signal and provide an output signal representing an amount of the filtered optical signal received; and

a neural network coupled to the at least one detector, the neural network capable of learning and performing pattern recognition, the neural network to receive the output signal from the at least one detector and determine the strain on the structure based on the learning and the performing of the pattern recognition and the output signal.

**2.** The system of claim 1, further comprising:

an analysis subsystem to receive a further signal from the neural network for further processing and analysis.

**3.** The system of claim 1, wherein the optical sensor includes at least one of a fiber optical sensor or Bragg optical grating sensor.

**4.** The system of claim 1, wherein the number of filters of the at least one filter is equal to a number of detectors of the at least one detector.

**5.** The system of claim 1, wherein a number of filters of the at least one filter is one less than a number of detectors of the at least one detector.

**6.** The system of claim 1, wherein the neural network has characteristics of the at least one filter and uses the characteristics when determining the strain on the structure.

**7.** The system of claim 1, wherein the at least one filter includes a plurality of filters and the at least one detector includes a plurality of detectors, at least some filters of the plurality of filters having a different frequency range, at least some detectors of the plurality of detectors having a different output signal reflecting the different frequency range of a coupled filter, and the neural network to receive a plurality of different output signals from the plurality of detectors and determine the strain on the structure based on the learning and the performing of the pattern recognition and the different output signals.

**8.** The system of claim 1, wherein the at least one filter includes at least three filters, a first filter of the at least three filters having a first filter profile that is monotonically non-decreasing with a particular wave length of the at least one wavelength, a second filter of the at least three filters having a second filter profile that is monotonically non-increasing with the particular wavelength, and a third filter of the at least three filters having a third filter profile that is approximately centered with a zero strain point of the optical sensor.

**9.** The system of claim 1, wherein the neural network includes a plurality of interunit connection strengths, and the learning and the performing of the pattern recognition is at least performed by the plurality of interunit connection strengths.

**10.** The system of claim 1, wherein the neural network generates functional mapping from non-linear learning from data, and wherein capability of the learning and the performing of the pattern recognition is based on the functional mapping.

**11.** The system of claim 1, wherein at least some of characteristics of the at least one filter are not sufficiently known to have a functional mapping.

**12.** the system of claim 1, wherein the one or more filters include a low profile filter and a high profile filter, the low profile filter to provide a nearly linear change in a first linearly changed output signal to the neural network and the high profile filter to provide the nearly linear change in a second linearly changed output signal to the neural network, wherein the neural network receives the first linearly changed output signal and the second linearly changed output signal and determines the strain on the structure based on the learning, the performing of the pattern recognition, and the output signal.

**13.** the system of claim 1, wherein the at least one detector includes a proportional integration spectrum detector, the proportional integration spectrum detector to output a proportional output integration signal that is proportional to the integration of a spectrum of the reflected optical signal multiplied by a respective filter of the at least one filter, and wherein the neural network determines the strain on the structure based on the learning and the performing of the pattern recognition and the proportional output integration signal.

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14. A method comprising:  
 receiving a reflected optical signal from an optical sensor,  
 the optical sensor coupled to a structure, at least one  
 wavelength of the reflected optical signal being spread  
 based on a strain being applied to the structure;  
 replicating the reflected optical signal to produce a plural-  
 ity of optical signals;  
 filtering at least one of the plurality of optical signals to  
 produce at least one filtered optical signal;  
 detecting the at least one filtered optical signal to determine  
 an output signal representing an amount of the filtered  
 optical signal received; and  
 using a neural network to perform a neural network analy-  
 sis on the output signal to determine an amount of strain  
 applied to the structure, the neural network capable of  
 learning and performing pattern recognition.

15. The method of claim 14, wherein detecting further  
 comprises:  
 detecting an unfiltered optical signal from the plurality of  
 optical signals to determine the voltage output propor-  
 tional to an amount of the unfiltered optical signal.

16. The method of claim 14, wherein performing the neural  
 network analysis comprises:  
 preprocessing the output signal; and  
 performing the neural network analysis on the prepro-  
 cessed output to determine the amount of strain applied  
 to the structure.

17. The method of claim 16, wherein preprocessing the  
 output signal comprises at least one of scaling the output  
 signal or normalizing the output signal.

18. The method of claim 14, wherein the filtering is per-  
 formed by a plurality of filters having a different frequency  
 range, the detecting is performed by a plurality of detectors  
 having a different output signal reflecting the different fre-  
 quency range of a coupled filter, and the neural network to

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perform the neural network analysis on a plurality of different  
 output signals from the plurality of detectors to determine the  
 strain applied to the structure.

19. A method comprising:  
 receiving a reflected optical signal from an optical sensor,  
 the optical sensor coupled to a structure, at least one  
 wavelength of the reflected optical signal being spread  
 based on a strain being applied to the structure;  
 decomposing the reflected optical signal to produce a plu-  
 rality of different components of the reflected optical  
 signal;  
 filtering the plurality of different components to produce a  
 plurality of filtered components;  
 detecting the plurality of filtered components to determine  
 an output signal representing an amount of at least one of  
 the plurality of filtered components; and  
 using a neural network to perform a neural network analy-  
 sis on the output signal to determine an amount of strain  
 applied to the structure, the neural network capable of  
 learning and performing pattern recognition.

20. The method of claim 19, further comprising:  
 performing further processing and analysis on the amount  
 of strain applied to the structure.

21. The method of claim 19, wherein the at least one  
 wavelength of the reflected optical signal being spread based  
 on the strain is a center wavelength with a linear shift.

22. The method of claim 19, wherein the filtering is per-  
 formed by a plurality of filters having a different frequency  
 range, the detecting is performed by a plurality of detectors  
 having a different output signal reflecting the different fre-  
 quency range of a coupled filter, and the neural network to  
 perform the neural network analysis on a plurality of different  
 output signals from the plurality of detectors to determine the  
 strain applied to the structure.

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